filed 5/13/04

## **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

ETCHING OPENINGS OF DIFFERENT DEPTHS USING A SINGLE MASK LAYER METHOD AND STRUCTURE

Application Number:

10/209564

Confirmation Number:

First Named Applicant:

David Dobuzinsky

Attorney Docket Number:

FIS920040046us1

Art Unit:

2823

Examiner:

Phan

Search string:

(6709978 or 6710447 or 6667223 or 6617224 or 6541349 or 6180489 or 6303733 or 6426558 or 6303447 or 6430028 or 6387765 or 6444542 or 6124421 or 6214423 or 6348374 or 6124216 or 6008540 or 6339002 or 5422309 or 6110648 or 6265303 or 6221780 or 6255211 or 6566276 or 6406963 or 6361837 or 6211035 or 6351039

or 6472312 or 6025276 ).pn

## **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

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## Signature

Examiner Name		] ,	Date
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